

Search Notes

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10/669,212

Examiner

Chris C. Chu

Applicant(s)/Patent under
Reexamination

KIM ET AL.

Art Unit

2815

SEARCHED

Class	Subclass	Date	Examiner
257	E23.098, 714, 724 & 686	3/6/2007	C.C.

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Searched in US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; FPRS; and IBM_TDB;	3/6/2007	C.C.